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			Serial No.
nvention: SUBMICRO! AC-COUPLE	N THERMAL IMAGING METH ED IMAGING FOR THERMAL I	OD AND ENHANCED RESOLUTION OF INTEGRATE	UTION (SUPER-RESOLVED) D CIRCUITS
I hereby certify that the	following correspondence:		U.S. P.T. 039290 04/02
Information Disclosure	Citation (PTO-1449)(Page 1)		1050
	(Identify type o	f correspondence)	
January 4 (Date)			
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	UC01-161

Application Number

Applicant(s)

ALI SHAKOURI ET AL.

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*EXAMINER INITIAL	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
	Elad, Michael and Feuer, Arie; "RESTORATION OF A SINGLE SUPERRESOLUTION IMAGE FROM SEVERAL BLURRED, NOISY, AND UNDERSAMPLED MEASURED IMAGES," IEEE Transactions on Image Processing Vol. 6, No. 12, pp. 1646-1658, December, 1997.
	Hardie, Russell C., Barnard, Kenneth J., and Armstrong, Ernest E.; "JOINT MAP REGISTRATION AND HIGH-RESOLUTION IMAGE ESTIMATION USING A SEQUENCE OF UNDERSAMPLED IMAGES," IEEE Transactions on Image Processing, Vol. 6, No. 12, pp. 1621-1633, December, 1997.
	Nguyen, Nhat, Milanfar, Peyman, Golub, G.; "A COMPUTATIONALLY EFFICIENT SUPERRESOLUTION IMAGE RECONSTRUCTION ALGORITHM," IEEE Transactions on Image Processing, Vol. 10, No. 4, pp. 573-583, April, 2001.
	Schultz, Richard R. and Stevenson, Robert L.; "EXTRACTION OF HIGH-RESOLUTION FRAMES FROM VIDEO SEQUENCES," IEEE Transactions on Image Processing, Vol. 5, No. 6, pp. 996-1011, June, 1996.
	Irani, Michal and Peleg, Shmuel; "SUPER RESOLUTION FROM IMAGE SEQUENCES," Proceedings, 10th International Conference on Pattern Recognition, Vol. 2, pp. 115-120, June, 1990.
EXAMINER	DATE CONSIDERED
*EXAMINER: I	nitial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and